




PCN Number:	20141007001		PCN Date:	10/09/2014	
Title:	Die Conversion for select AUP LL Devices in DBV, DCK and DRL Packages				
Customer Contact:	PCN Manager	Phone:	+1(214)480-6037	Dept: Quality Services	
Proposed 1st Ship Date:	01/09/2015	Estimated Sample Availability:	Date provided at sample request.		
Change Type:					
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials
<input checked="" type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process
<input type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process
		<input type="checkbox"/>	Part number change		
PCN Details					
Description of Change:					
This change notification is to announce a Die Conversion for select AUP LL Devices. The Die Revision will change from X/A to C. Devices affected by this change are listed in the product affected section of this notification. There will be no change to the data sheet.					
Reason for Change:					
Continuity of Supply					
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):					
Reliability & electrical characterization evaluation showed no adverse impacts.					
Changes to product identification resulting from this PCN:					
Die Rev designator will change as shown in table & sample label below:					
Current		New			
Die Rev [2P]		Die Rev [2P]			
X/A		C			
Sample product shipping label to indicate die rev location (not actual product label)					
 MADE IN: Malaysia 2DC: 20:				(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) (2P) REV: (V) 0033317 (20L) OSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS	
MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39 LBL: 5A (L)T0:1750					
Die Rev Marking:					
Current = X/A					
New = C					

Product Affected:			
SN74AUP1G00DBVR	SN74AUP1G08DBVR	SN74AUP1G240DBVR	SN74AUP1G58DCKT
SN74AUP1G00DBVT	SN74AUP1G08DBVT	SN74AUP1G240DBVT	SN74AUP1G58DRLR
SN74AUP1G00DCKT	SN74AUP1G08DCKT	SN74AUP1G240DCKT	SN74AUP1G79DBVR
SN74AUP1G00DRLR	SN74AUP1G08DRLR	SN74AUP1G32DBVR	SN74AUP1G79DBVT
SN74AUP1G02DBVR	SN74AUP1G125DBVR	SN74AUP1G32DBVT	SN74AUP1G79DCKT
SN74AUP1G02DBVT	SN74AUP1G125DBVT	SN74AUP1G32DCKT	SN74AUP1G79DRLR
SN74AUP1G02DCKT	SN74AUP1G125DCKT	SN74AUP1G32DRLR	SN74AUP1G80DBVR
SN74AUP1G02DRLR	SN74AUP1G125DRLR	SN74AUP1G34DBVR	SN74AUP1G80DBVT
SN74AUP1G04DBVR	SN74AUP1G126DBVR	SN74AUP1G34DBVT	SN74AUP1G80DCKT
SN74AUP1G04DBVT	SN74AUP1G126DBVT	SN74AUP1G34DCKT	SN74AUP1G97DBVR
SN74AUP1G04DCKT	SN74AUP1G126DCKT	SN74AUP1G34DRLR	SN74AUP1G97DBVT
SN74AUP1G04DRLR	SN74AUP1G126DRLR	SN74AUP1G57DBVR	SN74AUP1G97DCKR
SN74AUP1G06DBVR	SN74AUP1G14DBVR	SN74AUP1G57DBVT	SN74AUP1G97DCKT
SN74AUP1G06DBVT	SN74AUP1G14DBVT	SN74AUP1G57DCKR	SN74AUP1G97DRLR
SN74AUP1G06DCKT	SN74AUP1G14DCKT	SN74AUP1G57DCKT	SN74AUP1G98DBVR
SN74AUP1G06DRLR	SN74AUP1G14DRLR	SN74AUP1G57DRLR	SN74AUP1G98DBVT
SN74AUP1G07DBVR	SN74AUP1G17DBVR	SN74AUP1G57DRLR-P	SN74AUP1G98DCKR
SN74AUP1G07DBVT	SN74AUP1G17DBVT	SN74AUP1G58DBVR	SN74AUP1G98DCKT
SN74AUP1G07DCKT	SN74AUP1G17DCKT	SN74AUP1G58DBVT	SN74AUP1G98DRLR
SN74AUP1G07DRLR	SN74AUP1G17DRLR	SN74AUP1G58DCKR	

Reference Qualification Data: (Approved 11/29/2010)

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.			
Qualification Device Construction Details:			
Qualification Vehicle #1: SN74AUP1G00DCKR			
Wafer Fab Site:	FREISING	Wafer Process:	P9722
Protective Die Coating:	10KACN		
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results			
Reliability Test	Conditions	Sample Size (PASS/FAIL)	
Electrical Char	Approved by Product Engineer	PASS	
ESD (CDM)	1500 V	3/0	
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS	
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS	
Notes: Qualification tests "pass" on zero fails for each test			
Qualification Vehicle #2: SN74AUP1G02DCKR			
Wafer Fab Site:	FREISING	Wafer Process:	P9722
Protective Die Coating:	10KACN		

Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size (PASS/FAIL)
Electrical Char	Approved by Product Engineer	PASS
ESD (CDM)	1500 V	3/0
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS
Notes: Qualification tests "pass" on zero fails for each test		
Qualification Vehicle #3: SN74AUP1G04DCKR		
Wafer Fab Site:	FREISING	Wafer Process: P9722
Protective Die Coating:	10KACN	
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size (PASS/FAIL)
Electrical Char	Approved by Product Engineer	PASS
ESD (CDM)	1500 V	3/0
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS
Notes: Qualification tests "pass" on zero fails for each test		
Qualification Vehicle #4: SN74AUP1G06DCKR		
Wafer Fab Site:	FREISING	Wafer Process: P9722
Protective Die Coating:	10KACN	
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size (PASS/FAIL)
Electrical Char	Approved by Product Engineer	PASS
ESD (CDM)	1500 V	3/0
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS
Notes: Qualification tests "pass" on zero fails for each test		
Qualification Vehicle #5: SN74AUP1G07DCKR		
Wafer Fab Site:	FREISING	Wafer Process: P9722
Protective Die Coating:	10KACN	
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size (PASS/FAIL)
Electrical Char	Approved by Product Engineer	PASS
ESD (CDM)	1500 V	3/0
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS
Notes: Qualification tests "pass" on zero fails for each test		

Qualification Vehicle #6: SN74AUP1G08DCKR			
Wafer Fab Site:	FREISING	Wafer Process:	P9722
Protective Die Coating:	10KACN		
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results			
Reliability Test	Conditions	Sample Size (PASS/FAIL)	
Electrical Char	Approved by Product Engineer	PASS	
ESD (CDM)	1500 V	3/0	
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS	
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS	
Notes: Qualification tests "pass" on zero fails for each test			
Qualification Vehicle #7: SN74AUP1G125DCKR			
Wafer Fab Site:	FREISING	Wafer Process:	P9722
Protective Die Coating:	10KACN		
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results			
Reliability Test	Conditions	Sample Size (PASS/FAIL)	
Electrical Char	Approved by Product Engineer	PASS	
ESD (CDM)	1500 V	3/0	
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS	
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS	
Notes: Qualification tests "pass" on zero fails for each test			
Qualification Vehicle #8: SN74AUP1G126DCKR			
Wafer Fab Site:	FREISING	Wafer Process:	P9722
Protective Die Coating:	10KACN		
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results			
Reliability Test	Conditions	Sample Size (PASS/FAIL)	
Electrical Char	Approved by Product Engineer	PASS	
ESD (CDM)	1500 V	3/0	
X-Ray	Bottom Side only	5/0	
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS	
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS	
Notes: Qualification tests "pass" on zero fails for each test			
Qualification Vehicle #9: SN74AUP1G14DCKR			
Wafer Fab Site:	FREISING	Wafer Process:	P9722
Protective Die Coating:	10KACN		

Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size (PASS/FAIL)
Electrical Char	Approved by Product Engineer	PASS
ESD (CDM)	1500 V	3/0
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS
Notes: Qualification tests "pass" on zero fails for each test		
Qualification Vehicle #10: SN74AUP1G17DCKR		
Wafer Fab Site:	FREISING	Wafer Process: P9722
Protective Die Coating:	10KACN	
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size (PASS/FAIL)
Electrical Char	Approved by Product Engineer	PASS
ESD (CDM)	1500 V	3/0
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS
Notes: Qualification tests "pass" on zero fails for each test		
Qualification Vehicle #11: SN74AUP1G240DCKR		
Wafer Fab Site:	FREISING	Wafer Process: P9722
Protective Die Coating:	10KACN	
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size (PASS/FAIL)
Electrical Char	Approved by Product Engineer	PASS
ESD (CDM)	1500 V	3/0
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS
Notes: Qualification tests "pass" on zero fails for each test		
Qualification Vehicle #12: SN74AUP1G32DCKR		
Wafer Fab Site:	FREISING	Wafer Process: P9722
Protective Die Coating:	10KACN	
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results		
Reliability Test	Conditions	Sample Size (PASS/FAIL)
Electrical Char	Approved by Product Engineer	PASS
ESD (CDM)	1500 V	3/0
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS
Notes: Qualification tests "pass" on zero fails for each test		

Qualification Vehicle #13: SN74AUP1G34DCKR			
Wafer Fab Site:	FREISING	Wafer Process:	P9722
Protective Die Coating:	10KACN		
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results			
Reliability Test	Conditions	Sample Size (PASS/FAIL)	
Electrical Char	Approved by Product Engineer	PASS	
ESD (CDM)	1500 V	3/0	
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS	
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS	
Notes: Qualification tests "pass" on zero fails for each test			
Qualification Vehicle #14: SN74AUP1G79DCKR			
Wafer Fab Site:	FREISING	Wafer Process:	P9722
Protective Die Coating:	10KACN		
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results			
Reliability Test	Conditions	Sample Size (PASS/FAIL)	
Electrical Char	Approved by Product Engineer	PASS	
ESD (CDM)	1500 V	3/0	
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS	
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS	
Notes: Qualification tests "pass" on zero fails for each test			
Qualification Vehicle #15: SN74AUP1G80DCKR			
Wafer Fab Site:	FREISING	Wafer Process:	P9722
Protective Die Coating:	10KACN		
Qualification: <input type="checkbox"/> Plan <input checked="" type="checkbox"/> Test Results			
Reliability Test	Conditions	Sample Size (PASS/FAIL)	
Electrical Char	Approved by Product Engineer	PASS	
ESD (CDM)	1500 V	3/0	
Manufacturability	Wafer Fab (per mfg. Site specification)	PASS	
Manufacturability-TQ	Assembly (per mfg. Site specification)	PASS	
Notes: Qualification tests "pass" on zero fails for each test			

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com